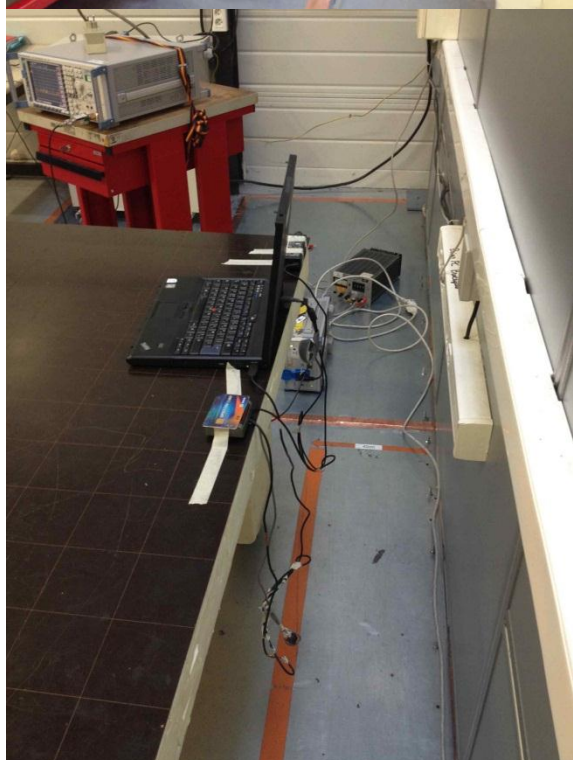
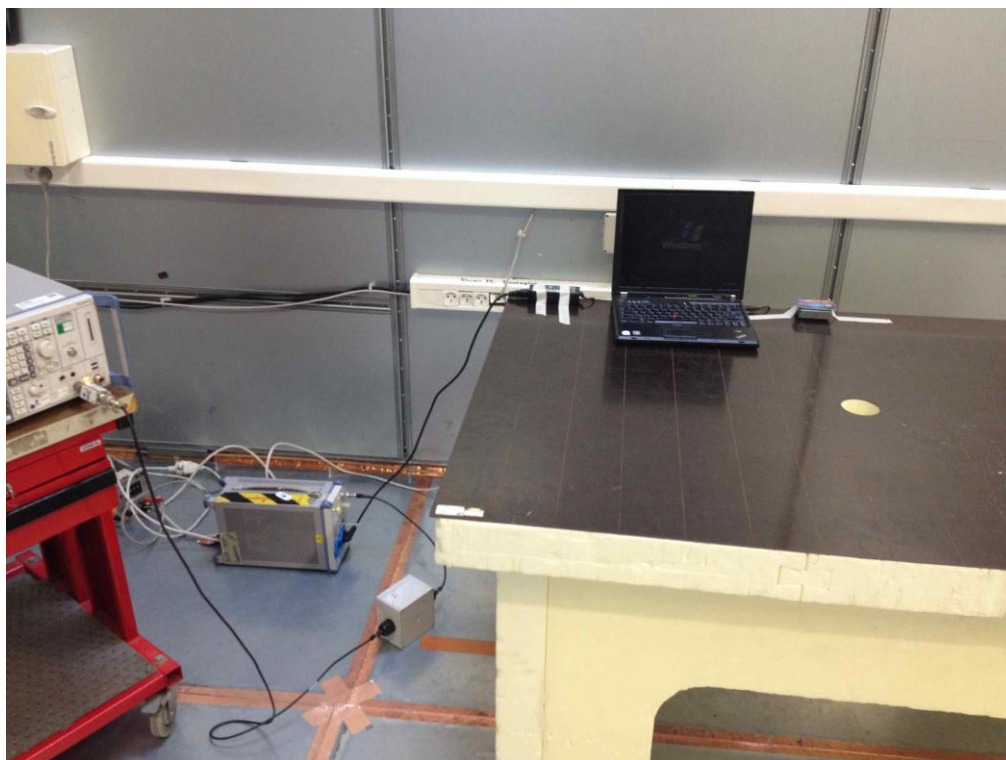


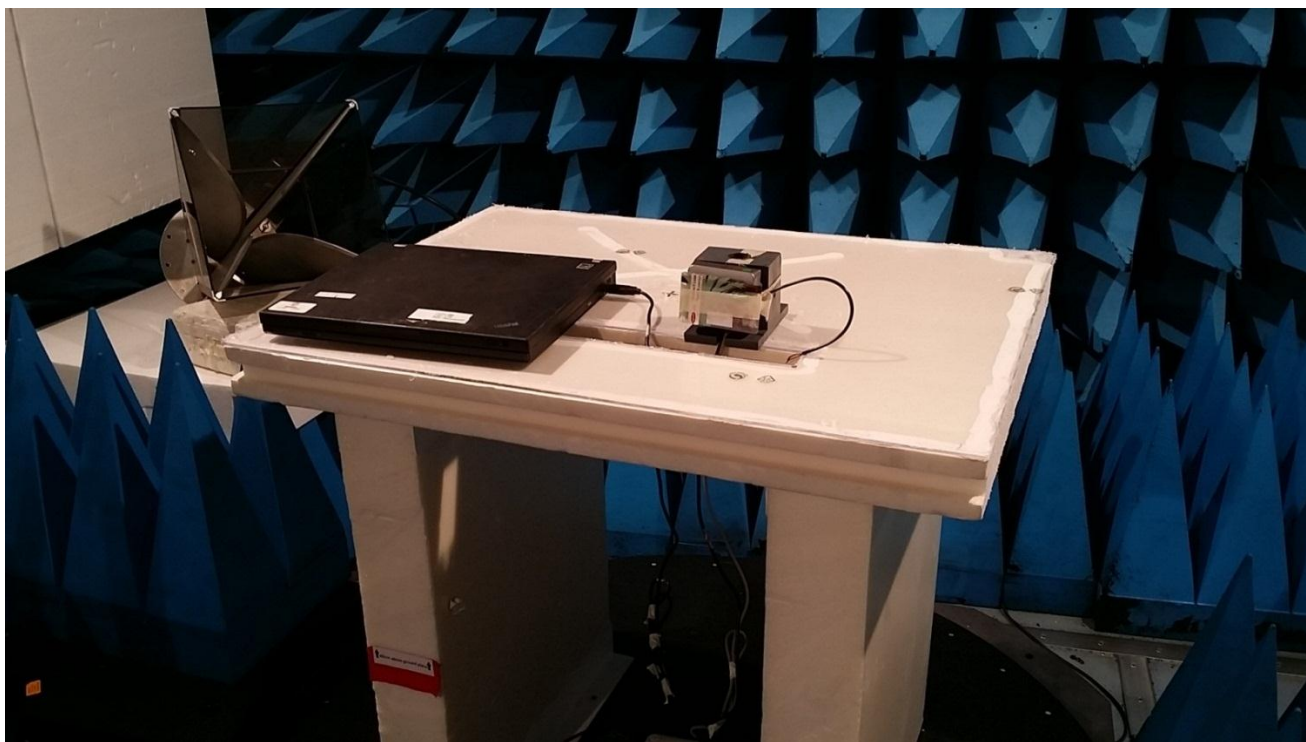
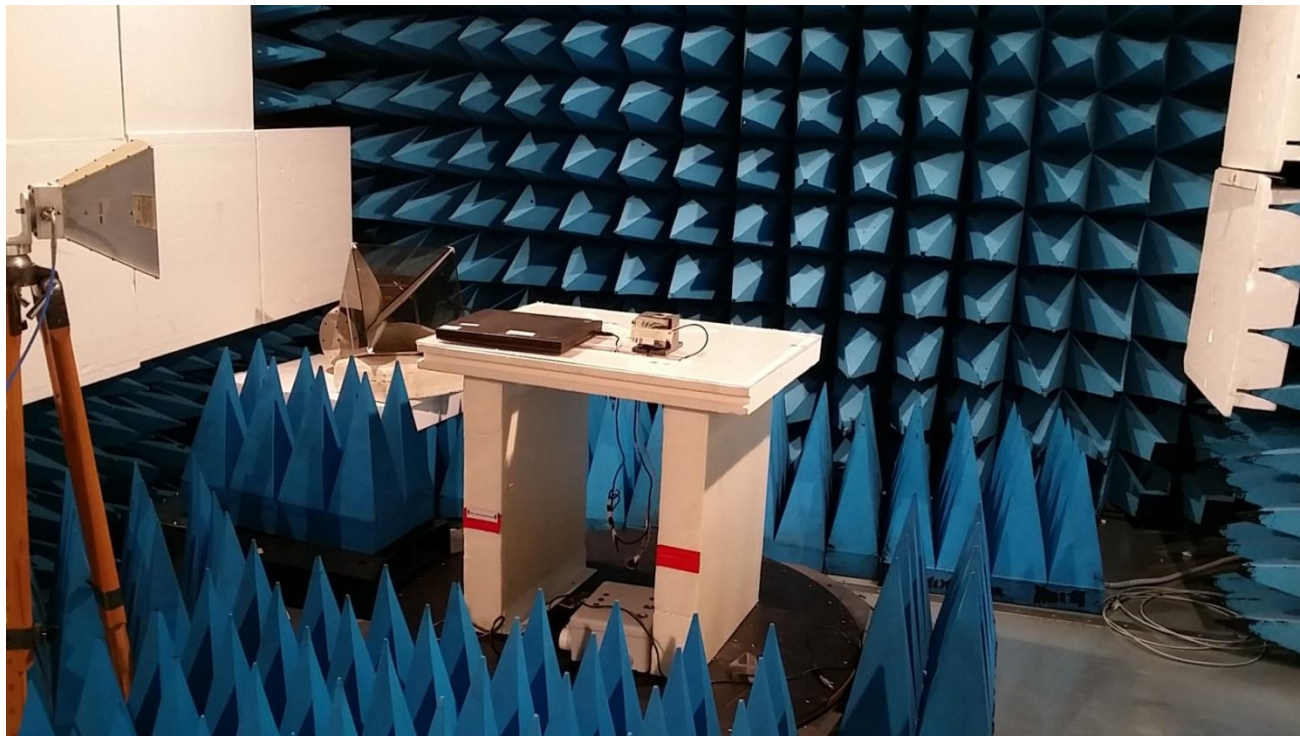
CONDUCTED AND RADIATED MEASUREMENT PHOTO

FCCID: XKB-IUC16XCL

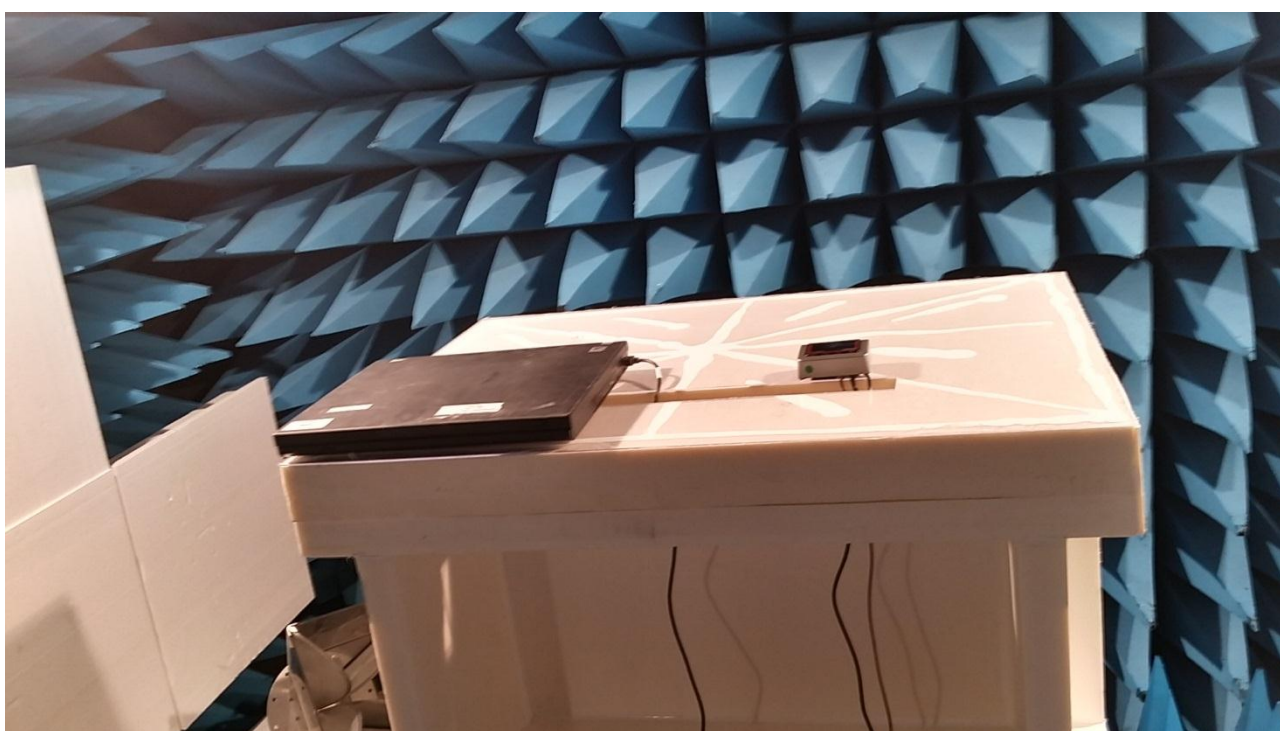
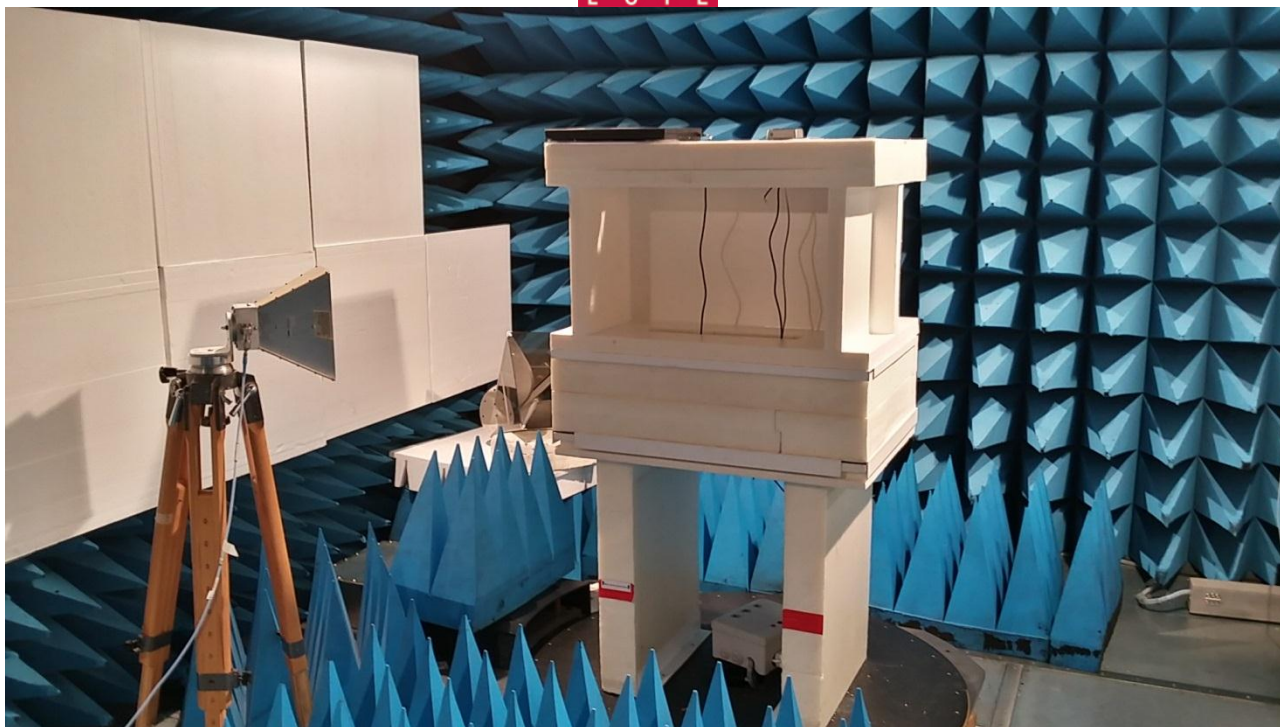
1.1 Conducted emission



1.2 Radiated emissions



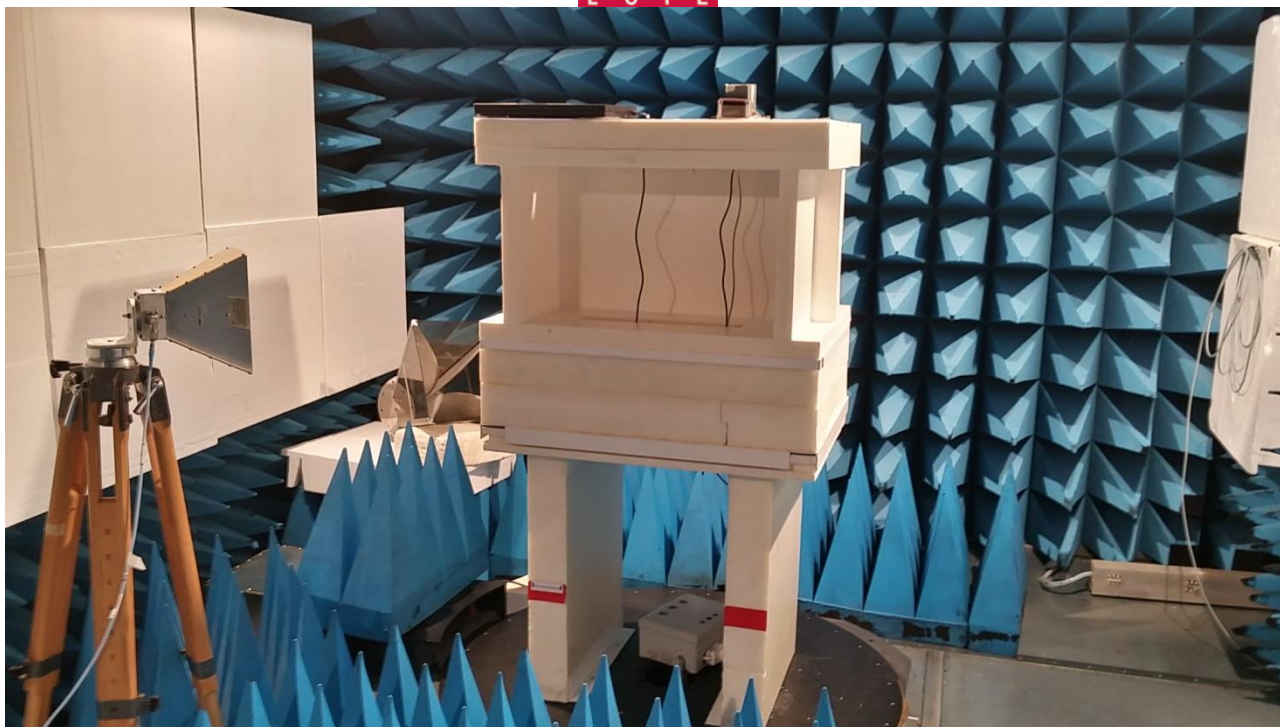
Test setup in anechoic chamber (Pos Z)



Test setup in anechoic chamber (Pos XY) – setup >1GHz



LCIE



Test setup in anechoic chamber (Pos Z) – setup >1GHz